

Application/Control No.	Applicant(s)/Patent under Reexamination								
10/660,078	RHEE, SHIN W.								
Examiner	Art Unit								
Jacob V Chai	2075								

ORIGINAL				CRO	SS REFEREN	E(S)		
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INTERNATIONAL CLASSIFICATION								
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(Legal Instruments Examiner) (Date)	(Pri	nary Examiner	Command P	ate) /			116

[c	laims renumbered in the same order as presented by applicant							cant	☐ CPA			☐ T.D.		☐ R.1.47					
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